

INTERNATIONAL STANDARD



**Measurement techniques of piezoelectric, dielectric and electrostatic
oscillators –
Part 1: Basic methods for the measurement**



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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**MEASUREMENT TECHNIQUES OF PIEZOELECTRIC,
DIELECTRIC AND ELECTROSTATIC OSCILLATORS –****Part 1: Basic methods for the measurement**

FOREWORD

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International Standard IEC 62884-1 has been prepared by IEC technical committee 49: Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection.

The text of this International Standard is based on the following documents:

CDV	Report on voting
49/1187A/CDV	49/1200/RVC

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62884 series, published under the general title *Measurement techniques of piezoelectric, dielectric and electrostatic oscillators*, can be found on the IEC website.

A bilingual version of this publication may be issued at a later date.

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MEASUREMENT TECHNIQUES OF PIEZOELECTRIC, DIELECTRIC AND ELECTROSTATIC OSCILLATORS –

Part 1: Basic methods for the measurement

1 Scope

This part of IEC 62884 specifies the measurement techniques for piezoelectric, dielectric and electrostatic oscillators, including Dielectric Resonator Oscillators (DROs) and oscillators using FBAR (hereinafter referred to as "Oscillator").

NOTE Dielectric Resonator Oscillators (DROs) and oscillators using FBAR are under consideration.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60027 (all parts), *Letter symbols to be used in electrical technology*

IEC 60050-561, *International electrotechnical vocabulary – Part 561: Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection*. Available at <http://www.electropedia.org>

IEC 60068-1:2013, *Environmental testing – Part 1: General and guidance*

IEC 60068-2-1, *Environmental testing – Part 2-1: Tests – Test A: Cold*

IEC 60068-2-2, *Environmental testing – Part 2-2: Tests – Test B: Dry heat*

IEC 60068-2-6, *Environmental testing – Part 2-6: Tests – Test Fc: Vibration (sinusoidal)*

IEC 60068-2-7, *Basic environmental testing procedures – Part 2-7: Tests – Test Ga and guidance: Acceleration, steady state*

IEC 60068-2-10:2005, *Environmental testing – Part 2-10: Tests – Test J and guidance: Mould growth*

IEC 60068-2-13, *Basic environmental testing procedures – Part 2-13: Tests – Test M: Low air pressure*

IEC 60068-2-14, *Environmental testing – Part 2-14: Tests – Test N: Change of temperature*

IEC 60068-2-17:1994, *Basic environmental testing procedures – Part 2-17: Tests – Test Q: Sealing*

IEC 60068-2-20, *Environmental testing – Part 2-20: Tests – Test T: Test methods for solderability and resistance to soldering heat of devices with leads*

IEC 60068-2-21, *Environmental testing – Part 2-21: Tests – Test U: Robustness of terminations and integral mounting devices*